

EiceDRIVER™ Compact

High voltage gate driver IC

2EDL family

600 V half bridge gate drive IC

2EDL05I06PF

2EDL05I06PJ

2EDL05I06BF

2EDL05N06PF

2EDL05N06PJ

EiceDRIVER™ Compact

Final datasheet

<Revision 2.6>, 01.06.2016

Final

Edition 01.06.2016

**Published by
Infineon Technologies AG
81726 Munich, Germany**

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Revision History

| Page or Item | Subjects (major changes since previous revision) |
|---|--|
| <Revision 0.85>, 16.04.2013 | |
| all | change term VCC in VDD |
| | |
| | |
| pp.16 | Introduced lopk+ and lopk- values |
| all | introduced 2EDL05N06PJ |
| all | introduced 2EDL05I06PJ |
| <Revision 2.6>, 01.06.2016 | |
| Update maximum Ta from 95°C to 105°C in Table 5 | |
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Last Trademarks Update 2010-10-26

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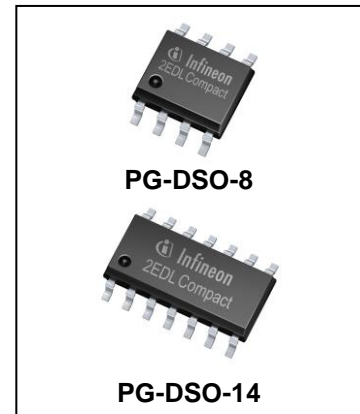
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EiceDRIVER™ Compact 600 V half bridge gate drive IC

1 Overview

Main features

- Thin-film-SOI-technology
- Maximum blocking voltage +600V
- Individual control circuits for both outputs
- Filtered detection of under voltage supply
- All inputs clamped by diodes
- Active shut down function
- Asymmetric undervoltage lockout thresholds for high side and low side
- Qualified according to JEDEC¹ (high temperature stress tests for 1000h) for target applications



Product highlights

- Insensitivity of the bridge output to negative transient voltages up to -50V given by SOI-technology
- Ultra fast bootstrap diode

Typical applications

- Home appliances
- Consumer electronics
- Fans, pumps
- General purpose drives

Product family

Table 1 Members of 2EDL family

| Sales Name | Special function | output current | Target transistor | typ. LS UVLO-thresholds | Bootstrap diode | Package |
|----------------------------|---------------------|----------------|-------------------|-------------------------|-----------------|-----------------|
| 2EDL05I06PF 2EDL05I06PJ | deadtime, interlock | 0.5 A | IGBT | 12.5 V / 11.6 V | Yes | DSO-8 DSO-14 |
| 2EDL05I06BF | – | 0.5 A | IGBT | 12.5 V / 11.6 V | Yes | DSO-8 |
| 2EDL05N06PF 2EDL05N06PJ | deadtime, interlock | 0.5 A 0.5 A | MOSFET | 9.1 V / 8.3 V | Yes | DSO-8 DSO-14 |

¹ J-STD-020 and JESD-022

Description

The 2EDL family contains devices, which control power devices like MOS-transistors or IGBTs with a maximum blocking voltage of +600V in half bridge configurations. Based on the used SOI-technology there is an excellent ruggedness on transient voltages. No parasitic thyristor structures are present in the device. Hence, no parasitic latch up may occur at all temperature and voltage conditions.

The two independent drivers outputs are controlled at the low-side using two different CMOS resp. LSTTL compatible signals, down up to 3.3V logic. The device includes an under-voltage detection unit with hysteresis characteristic which are optimised either for IGBT or MOSFET.

Those parts, which are designed for IGBT have asymmetric undervoltage lockout levels, which support strongly the integrated ultrafast bootstrap diode. Additionally, the offline gate clamping function provides an inherent protection of the transistors for parasitic turn-on by floating gate conditions, when the IC is not supplied via VDD.

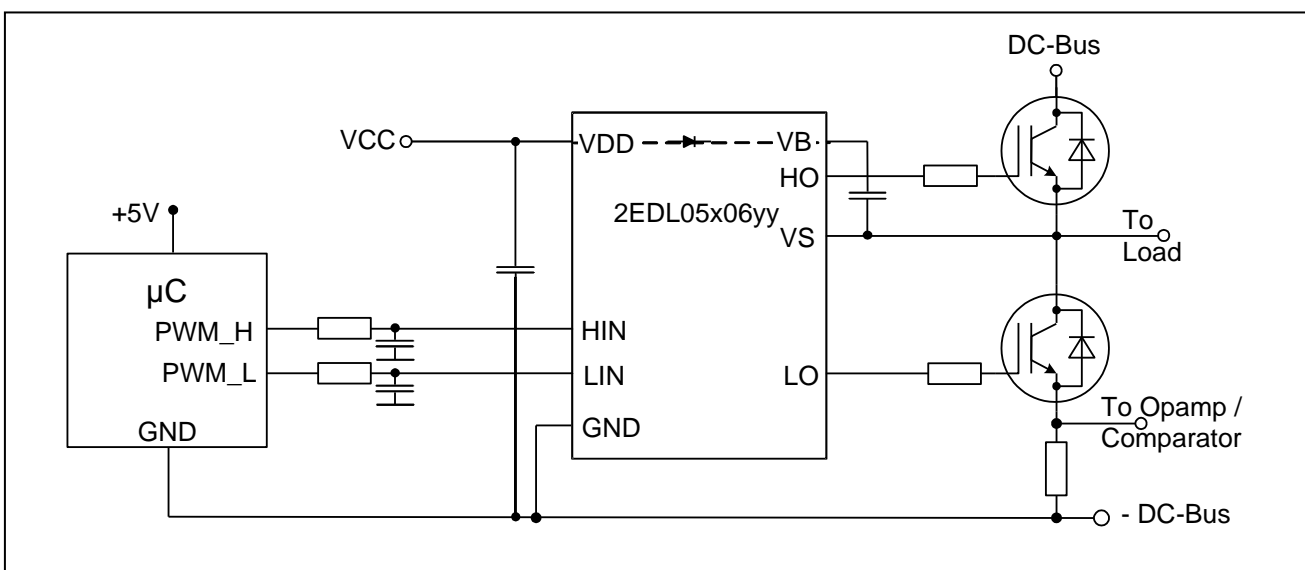


Figure 1 Typical Application
SO8 / SO14 package 0.5 A

2 Blockdiagram

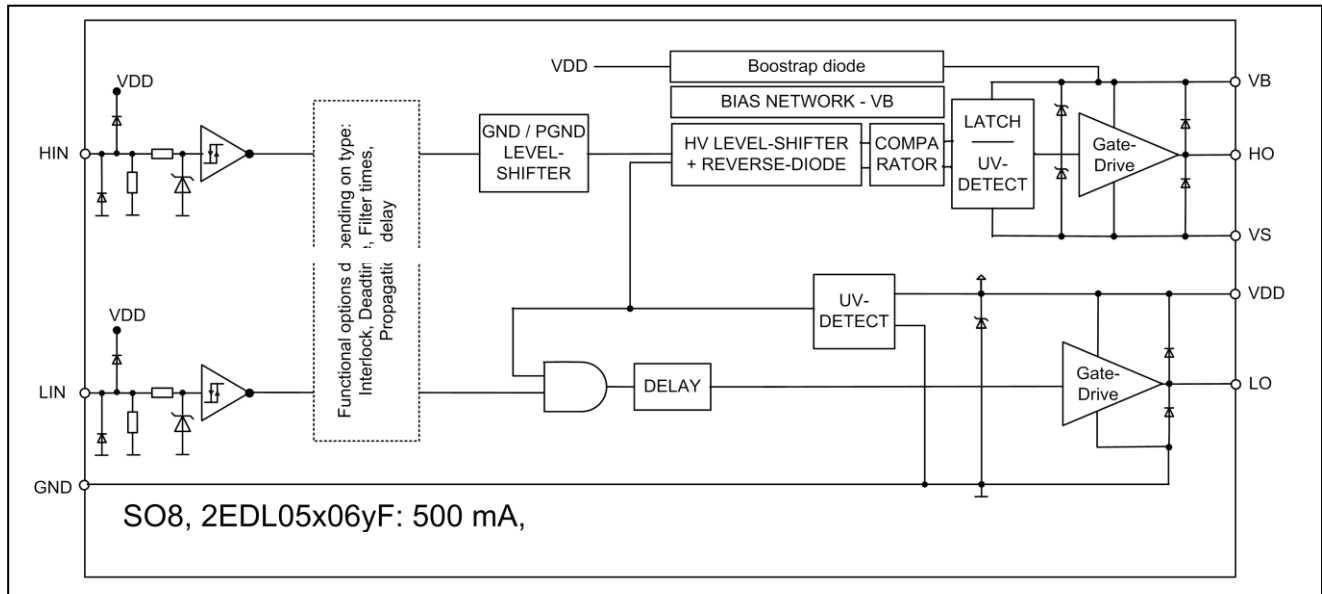


Figure 2 Block diagram for 2EDL05x06Py

3 Pin configuration, description, and functionality

3.1 Pin Configuration and Description

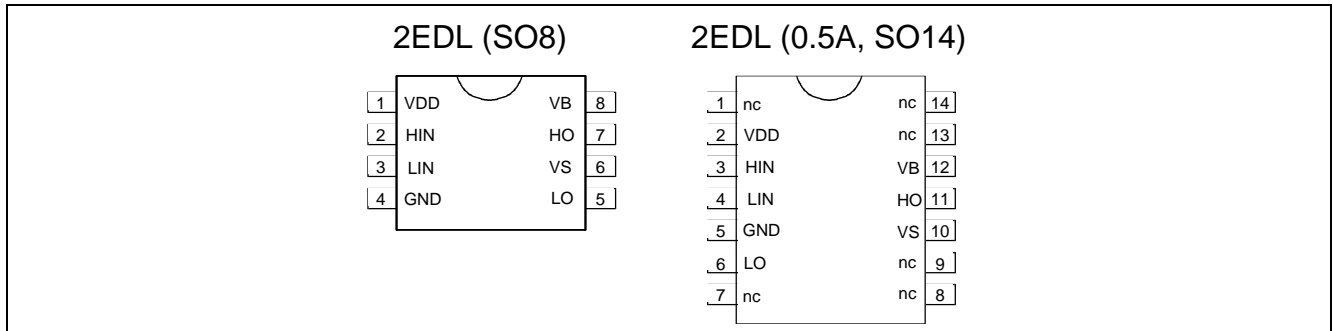


Figure 3 Pin Configuration of 2EDL family

Table 2 Pin Description

| Symbol | Description |
|--------|---------------------------------|
| VDD | Low side power supply |
| GND | Logic ground |
| HIN | High side logic input |
| LIN | Low side logic input |
| VB | High side positive power supply |
| HO | High side gate driver output |
| VS | High side negative power supply |
| LO | Low side gate driver output |
| nc | Not Connected |

3.2 Low Side and High Side Control Pins (LIN, HIN)

3.2.1 Input voltage range

All input pins have the capability to process input voltages up to the supply voltage of the IC. The inputs are therefore internally clamped to VDD and GND by diodes. An internal pull-down resistor is high ohmic, so that it can keep the IC in a safe state in case of PCB crack.

3.2.2 Switching levels

The Schmitt trigger input threshold is such to guarantee LSTTL and CMOS compatibility down to 3.3 V controller outputs. The input Schmitt trigger and noise filter provide beneficial noise rejection to short input pulses according to Figure 4 and Figure 5. Please note, that the switching levels of the input structures remain constant even though they can accept amplitudes up to the IC supply level.

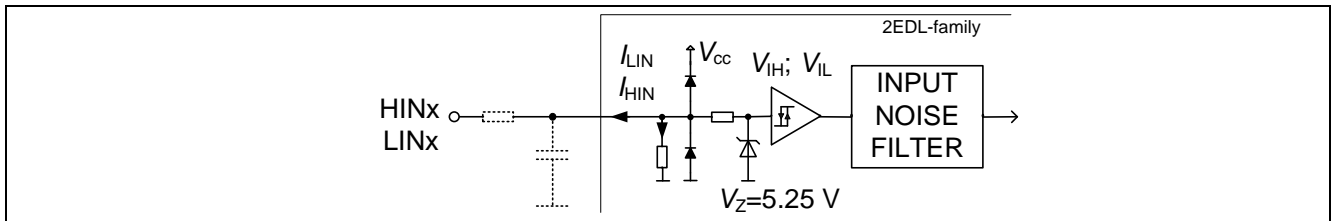


Figure 4 Input pin structure

3.2.3 Input filter time

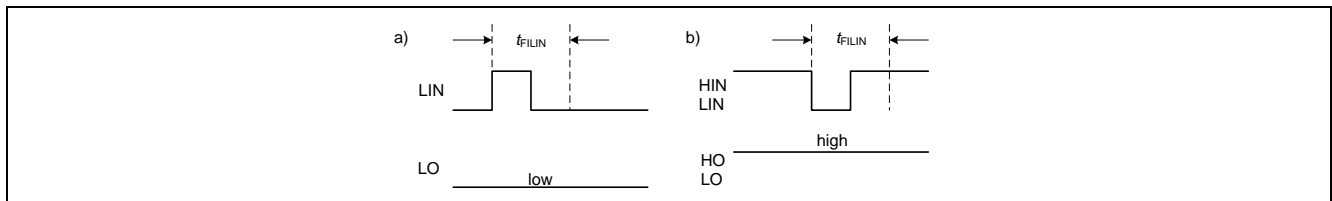


Figure 5 Input filter timing diagram

Short pulses are suppressed by means of an input filter. All IC, which have undervoltage lockout (UVLO) thresholds for MOSFET, have an input filter time of $t_{FILIN} = 75\text{ns}$ typ. and 150ns max. All IC having UVLO thresholds for IGBT have filter times of $t_{FILIN} = 150\text{ns}$ min and 200ns typ.

3.3 VDD and GND

VDD is the low side supply and it provides power to both the input logic and the low side output power stage. The input logic is referenced to GND ground as well as the under-voltage detection circuit. Output power stage is also referenced to GND ground.

The undervoltage lockout circuit enables the device to operate at power on when a typical supply voltage higher than V_{DDUV+} is present. Please see section 3.6 “Undervoltage lockout” for further information.

A filter time of typ. $1.8\mu\text{s}$ helps to suppress noise from the UVLO circuit, so that negative going voltage spikes at the supply pins will avoid parasitic UVLO events.

3.4 VB and VS (High Side Supplies)

VB to VS is the high side supply voltage. The high side circuit can float with respect to GND following the external high side power device emitter/source voltage. Due to the low power consumption, the floating driver stage can be supplied by bootstrap topology connected to VDD. A filter time of typ. $1.8\mu\text{s}$ helps to suppress noise from the UVLO circuit, so that negative going voltage spikes at the supply pins will avoid parasitic UVLO events.

The under-voltage circuit enables the device to operate at power on when a typical supply voltage higher than V_{DDUV+} is present. Please see section 3.6 “Undervoltage lockout” for further information. Details on bootstrap supply section and transient immunity can be found in application note [EiceDRIVER™ 2EDL family: Technical description](#).

3.5 LO and HO (Low and High Side Outputs)

Low side and high side power outputs are specifically designed for pulse operation such as gate drive for IGBT and MOSFET devices. Low side output is state triggered by the respective input, while high side output is edge triggered by the respective input. In particular, after an undervoltage condition of the VBS supply, a new turn-on signal (edge) is necessary to activate the high side output. In contrast, the low side outputs switch to the state of their respective inputs after an undervoltage condition of the VDD supply.

The output current specification I_{O+} and I_{O-} is defined in a way, which considers the power transistors miller voltage. This helps to design the gate drive better in terms of the application needs. Nevertheless, the devices are also characterised for the value of the pulse short circuit value I_{Opk+} and I_{Opk-} .

3.6 Undervoltage lockout (UVLO)

Two different UVLO options are required for IGBT and MOSFET. The types 2EDL05I06Px and 2EDL05I06BF are designed to drive IGBT. There are higher levels of undervoltage lockout for the low side UVLO than for the high side. This supports an improved start up of the IC, when bootstrapping is used. The thresholds for the low side are typically $V_{DDUV+} = 12.5$ V (positive going) and $V_{DDUV-} = 11.6$ V (negative going). The thresholds for the high side are typically $V_{BSUV+} = 11.6$ V (positive going) and $V_{BSUV-} = 10.7$ V (negative going).

The types 2EDL05N06Px are designed to drive power MOSFET. A similar distinction for the high side and low side UVLO threshold as for IGBT is not realised here. The IC shuts down all the gate drivers power outputs, when the supply voltage is below typ. $V_{DDUV-} = 8.3$ V (min. / max. = 7.5 V / 9 V). The turn-on threshold is typ. $V_{DDUV+} = 9.1$ V (min. / max. = 8.3 V / 9.9 V)

3.7 Bootstrap diode

An ultra fast bootstrap diode is monolithically integrated for establishing the high side supply. The differential resistor of the diode helps to avoid extremely high inrush currents when charging the bootstrap capacitor initially.

3.8 Deadtime and interlock function

The IC provides a hardware fixed deadtime. The deadtime is different for the two MOSFET types (2EDL05N06Px) and for the two IGBT types (2EDL05I06Px). The deadtimes are particularly typ. 380 ns for IGBT and typ. 75 ns for MOSFET. An additional interlock function prevents the two outputs from being activated simultaneously.

The part 2EDL05I06BF does not have the deadtime feature and also not the interlock function. Here, the two outputs can be activated simultaneously.

¹ Not subject of production test, verified by characterisation

4 Electrical Parameters

4.1 Absolute Maximum Ratings

All voltages are absolute voltages referenced to V_{GND} -potential unless otherwise specified. ($T_a=25^\circ\text{C}$)

Table 3 Abs. maximum ratings

| Parameter | Symbol | Min. | Max. | Unit | |
|--|-----------|--------------------|-----------------|------------------|-----|
| High side offset voltage(Note 1) | V_S | $V_{DD}-V_{BS}-6$ | 600 | V | |
| High side offset voltage ($t_p<500\text{ns}$, Note 1) | | $V_{DD}-V_{BS}-50$ | – | | |
| High side offset voltage(Note 1) | V_B | $V_{DD}-6$ | 620 | | |
| High side offset voltage ($t_p<500\text{ns}$, Note 1) | | $V_{DD}-50$ | – | | |
| High side floating supply voltage (V_B vs. V_S) (internally clamped) | V_{BS} | -1 | 20 | | |
| High side output voltage (V_{HO} vs. V_S) | V_{HO} | -0.5 | $V_B + 0.5$ | | |
| Low side supply voltage (internally clamped) | V_{DD} | -1 | 20 | | |
| Low side output voltage (V_{LO} vs. V_{GND}) | V_{LO} | -0.5 | $V_{GND} + 0.5$ | | |
| Input voltage LIN,HIN | V_{IN} | -0.5 | $V_{DD} + 0.5$ | | |
| Power dissipation (to package) (Note 2) | DSO8 | P_D | – | 0.6 | W |
| | DSO14 | | – | 0.85 | |
| Thermal resistance (junction to ambient, see section 6) | DSO8 | $R_{th(j-a)}$ | – | 195 | K/W |
| | DSO14 | | – | 139 | |
| Junction temperature (Note 3) | T_J | – | 150 | $^\circ\text{C}$ | |
| Storage temperature | T_S | - 40 | 150 | | |
| offset voltage slew rate (Note 4) | dV_S/dt | – | 50 | V/ns | |

Note :The minimum value for ESD immunity is 1.0kV (Human Body Model). ESD immunity inside pins connected to the low side (VDD, HIN, LIN, GND, LO) and pins connected inside each high side itself (VB, HO, VS) is guaranteed up to 1.5kV (Human Body Model) respectively.

Note 1 : In case $V_{DD} > V_B$ there is an additional power dissipation in the internal bootstrap diode between pins VDD and VB in case of activated bootstrap diode. Insensitivity of bridge output to negative transient voltage up to -50V is not subject to production test – verified by design / characterization.

Note 2: Consistent power dissipation of all outputs. All parameters are inside operating range.

Note 3: Qualification stress tests cover a max. junction temperature of 150°C for 1000 h.

Note 4: Not subject of production test, verified by characterisation.

4.2 Required operation conditions

All voltages are absolute voltages referenced to V_{GND} -potential unless otherwise specified. ($T_a = 25^\circ\text{C}$)

Table 4 Required Operation Conditions

| Parameter | Symbol | Min. | Max. | Unit |
|--|----------|------|------|------|
| High side offset voltage (Note 1) | V_B | 7 | 620 | V |
| Low side supply voltage (internally clamped) | V_{DD} | 10 | 20 | |

4.3 Operating Range

All voltages are absolute voltages referenced to V_{GND} -potential unless otherwise specified. ($T_a = 25^\circ\text{C}$)

Table 5 Operating range

| Parameter | | Symbol | Min. | Max. | Unit |
|---|--------------|--------------------|-----------------------|----------|------------------|
| High side floating supply offset voltage | | V_S | $V_{DD} - V_{BS} - 1$ | 500 | V |
| High side floating supply offset voltage (V_B vs. V_{DD} , statically) | | V_{BDD} | -1.0 | 500 | |
| High side floating supply voltage (V_B vs. V_S , Note 1) | IGBT-Types | V_{BS} | 13 | 17.5 | |
| | MOSFET-Types | | 10 | 17.5 | |
| High side output voltage (V_{HO} vs. V_S) | | V_{HO} | 10 | V_{BS} | |
| Low side output voltage (V_{LO} vs. V_{GND}) | | V_{LO} | 0 | V_{DD} | |
| Low side supply voltage | IGBT-Types | V_{DD} | 13 | 17.5 | |
| | MOSFET-Types | | 10 | 17.5 | |
| Logic input voltages LIN,HIN (Note 2) | | V_{IN} | 0 | 17.5 | |
| Pulse width for ON or OFF (Note 3) | IGBT-Types | t_{IN} | 0.8 | – | |
| | MOSFET-Types | | 0.3 | – | |
| Ambient temperature | | T_a | -40 | 105 | $^\circ\text{C}$ |
| Thermal coefficient (junction to top, see section 6) | DSO8 | $\Psi_{th(j-top)}$ | – | 8.0 | K/W |
| | DSO14 | | – | 6.0 | |

Note 1 : Logic operational for V_B (V_B vs. V_{GND}) > 7.0V

Note 2 : All input pins (HIN, LIN) are internally clamped (see abs. maximum ratings)

Note 3 : The input pulse may not be transmitted properly in case of input pulse width at LIN and HIN below 0.8 μs (IGBT types) or 0.3 μs (MOSFET) respectively

4.4 Static logic function table

| VDD | VBS | LO | HO |
|--------------|--------------|-----|-----|
| $<V_{DDUV-}$ | X | 0 | 0 |
| 15V | $<V_{BSUV-}$ | LIN | 0 |
| 15V | 15V | 0 | 0 |
| 15V | 15V | 0 | 0 |
| 15V | 15V | LIN | HIN |

all voltages with reference to GND

4.5 Static parameters

$V_{DD} = V_{BS} = 15V$ unless otherwise specified. ($T_a = 25^\circ C$)

Table 6 Static parameters

| Parameter | Symbol | Values | | | Unit | Test condition | |
|---|--------------|-------------|---------------------------------------|--------------------------------|---------|---|--|
| | | Min. | Typ. | Max. | | | |
| High level input voltage | V_{IH} | 1.7 | 2.1 | 2.4 | V | | |
| Low level input voltage | V_{IL} | 0.7 | 0.9 | 1.1 | | | |
| High level output voltage | LO HO | V_{OH} | – $V_{DD} - 0.45$ $V_B - 0.45$ | $V_{DD} - 1$ $V_B - 1$ | | $I_O = -20\text{ mA}$ | |
| Low level output voltage | LO HO | V_{OL} | – $V_{GND} + 0.13$ $V_S + 0.13$ | $V_{GND} + 0.3$ $V_S + 0.3$ | | $I_O = 20\text{ mA}$ | |
| V_{DD} supply undervoltage positive going threshold | IGBT-types | V_{DDUV+} | 11.8 | 12.5 | | 13.2 | |
| | MOSFET types | | 8.3 | 9.1 | | 9.9 | |
| V_{BS} supply undervoltage positive going threshold | IGBT-types | V_{BSUV+} | 10.9 | 11.6 | | 12.4 | |
| | MOSFET types | | 8.3 | 9.1 | | 9.9 | |
| V_{DD} supply undervoltage negative going threshold | IGBT-types | V_{DDUV-} | 10.9 | 11.6 | | 12.4 | |
| | MOSFET types | | 7.5 | 8.3 | | 9 | |
| V_{BS} supply undervoltage negative going threshold | IGBT-types | V_{BSUV-} | 10 | 10.7 | 11.7 | | |
| | MOSFET types | | 7.5 | 8.3 | 9 | | |
| V_{DD} and V_{BS} supply UVLO hysteresis | IGBT-types | V_{DDUVH} | 0.5 | 0.9 | – | | |
| | MOSFET types | V_{BSUVH} | 0.5 | 0.9 | – | | |
| High side leakage current betw. VS and GND | I_{LVS+} | – | 1 | 12.5 | μA | $V_S = 600V$ | |
| High side leakage current betw. VS and GND | I_{LVS+}^1 | – | 10 | – | | $T_J = 125^\circ C$, $V_S = 600\text{ V}$ | |
| Quiescent current V_{BS} supply (VB only) | I_{QBS1} | – | 170 | 300 | | HO = low depending on current types | |
| Quiescent current V_{BS} supply (VB only) | I_{QBS2} | – | 170 | 300 | | HO = high depending on | |

¹ Not subject of production test, verified by characterisation

Table 6 Static parameters

| Parameter | Symbol | Values | | | Unit | Test condition |
|---|--------------|--------|------|------|---------------|---|
| | | Min. | Typ. | Max. | | |
| Quiescent current VDD supply (VDD only) | I_{QDD1} | – | 0.3 | 0.6 | mA | current types $V_{LIN} = \text{float}$. |
| Quiescent current VDD supply (VDD only) | I_{QDD2} | – | 0.28 | 0.6 | | $V_{LIN} = 3.3 \text{ V}$, $V_{HIN} = 0$ |
| Quiescent current VDD supply (VDD only) | I_{QDD3} | – | 0.28 | 0.6 | | $V_{LIN} = 0$, $V_{HIN} = 3.3 \text{ V}$ |
| Input bias current | I_{LIN+} | 15 | 35 | 60 | μA | $V_{LIN} = 3.3 \text{ V}$ |
| Input bias current | I_{LIN-} | – | 0 | – | | $V_{LIN} = 0$ |
| Input bias current | I_{HIN+} | 15 | 35 | 60 | | $V_{HIN} = 3.3 \text{ V}$ |
| Input bias current | I_{HIN-} | – | 0 | – | | $V_{HIN} = 0$ |
| Mean output current for load capacity charging in range from 3 V (20%) to 6 V (40%) | I_{O+} | 0.18 | 0.23 | – | A | $C_L = 22 \text{ nF}$ |
| Peak output current turn on (single pulse) | I_{Opk+}^1 | – | 0.36 | – | | $R_L = 0 \Omega$, $t_p < 10 \mu\text{s}$ |
| Mean output current for load capacity discharging in range from 12 V (80%) to 9 V (60%) | I_{O-} | 0.39 | 0.48 | – | | $C_L = 22 \text{ nF}$ |
| Peak output current turn off (single pulse) | I_{Opk-}^1 | – | 0.70 | – | | $R_L = 0 \Omega$, $t_p < 10 \mu\text{s}$ |
| Bootstrap diode forward voltage between VDD and VB | $V_{F,BSD}$ | – | 1.0 | 1.2 | V | $I_F = 0.3 \text{ mA}$ |
| Bootstrap diode forward current between VDD and VB | $I_{F,BSD}$ | 30 | 55 | 80 | mA | $V_{DD} - V_B = 4 \text{ V}$ |
| Bootstrap diode resistance | R_{BSD} | 20 | 36 | 54 | Ω | $V_{F1} = 4 \text{ V}$, $V_{F2} = 5 \text{ V}$ |

¹ Not subject of production test, verified by characterisation

4.6 Dynamic parameters

$V_{DD} = V_{BS} = 15\text{ V}$, $V_S = V_{GND}$, $C_L = 180\text{ pF}$ unless otherwise specified. ($T_A=25^\circ\text{C}$)

Table 7 Dynamic parameters

| Parameter | | Symbol | Values | | | Unit | Test condition | |
|--|--------------|-------------|--------|------|------|----------------------------------|--|------------------------------------|
| | | | Min. | Typ. | Max. | | | |
| Turn-on propagation delay | IGBT types | t_{on} | 280 | 420 | 610 | ns | $V_{LIN/HIN} = 0$ or 3.3 V | |
| | MOSFET types | | 210 | 310 | 460 | | | |
| Turn-off propagation delay | IGBT types | t_{off} | 260 | 400 | 590 | | | |
| | MOSFET types | | 200 | 300 | 440 | | | |
| Turn-on rise time | | t_r | – | 48 | 80 | | $V_{LIN/HIN} = 0$ or 3.3 V $C_L = 1\text{ nF}$ | |
| Turn-off fall time | | t_f | – | 24 | 40 | | | |
| Input filter time at LIN/HIN for turn on and off | IGBT types | t_{FILIN} | 120 | 192 | – | ns | $V_{LIN/HIN} = 0$ & 3.3 V | |
| | MOSFET types | | | | | | | |
| Dead time (not for 2EDL05I06BF) | IGBT types | DT | 260 | 380 | 540 | | ns | $V_{LIN/HIN} = 0$ & 3.3 V |
| | MOSFET types | | 30 | 75 | 140 | | | |
| Dead time matching $\text{abs}(DT_{LH} - DT_{HL})$ for single IC (not for 2EDL05I06BF) | IGBT types | MDT | – | 10 | 80 | ext. dead time 0ns | | |
| | MOSFET types | | | 10 | 50 | | | |
| Matching delay ON, $\text{abs}(ton_{HS} - ton_{LS})$ | | MT_{ON} | – | 10 | 60 | external dead time > 500 ns | | |
| Matching delay OFF, $\text{abs}(toff_{HS} - toff_{LS})$ | | MT_{OFF} | – | 10 | 60 | external dead time > 500 ns | | |
| Output pulse width matching. $PW_{in} - PW_{out}$ | IGBT types | PM | – | 20 | 80 | $PW_{in} > 1\text{ }\mu\text{s}$ | | |
| | MOSFET types | | – | 20 | 70 | | | |

5 Timing diagrams

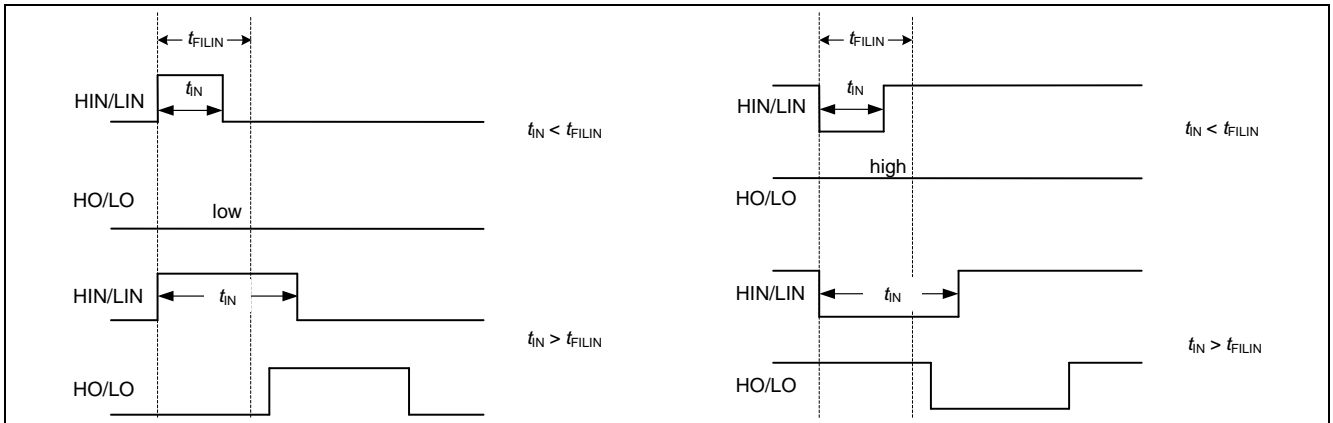


Figure 6 Timing of short pulse suppression

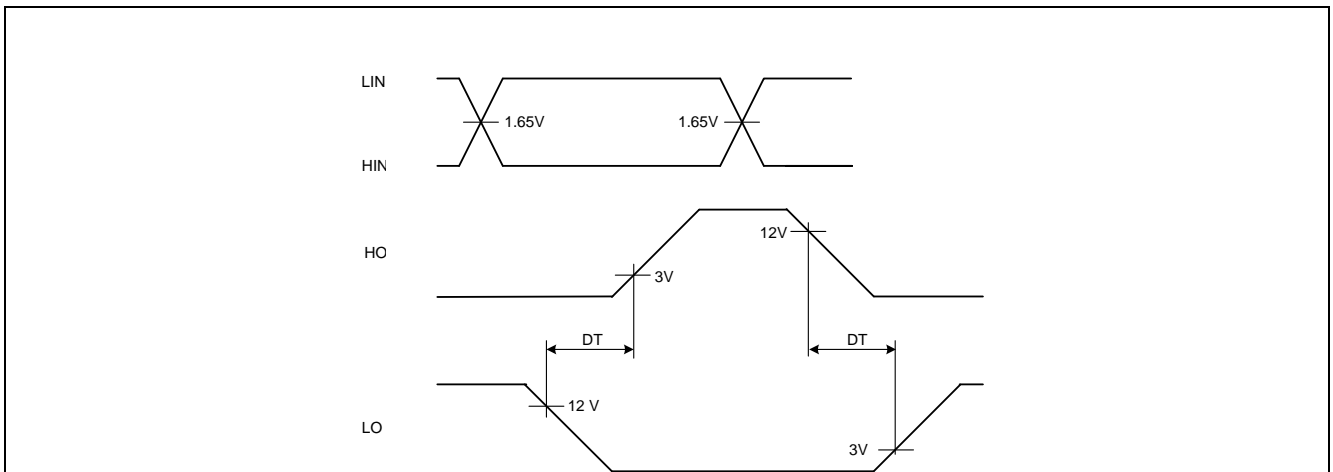


Figure 7 Timing of of internal deadtime

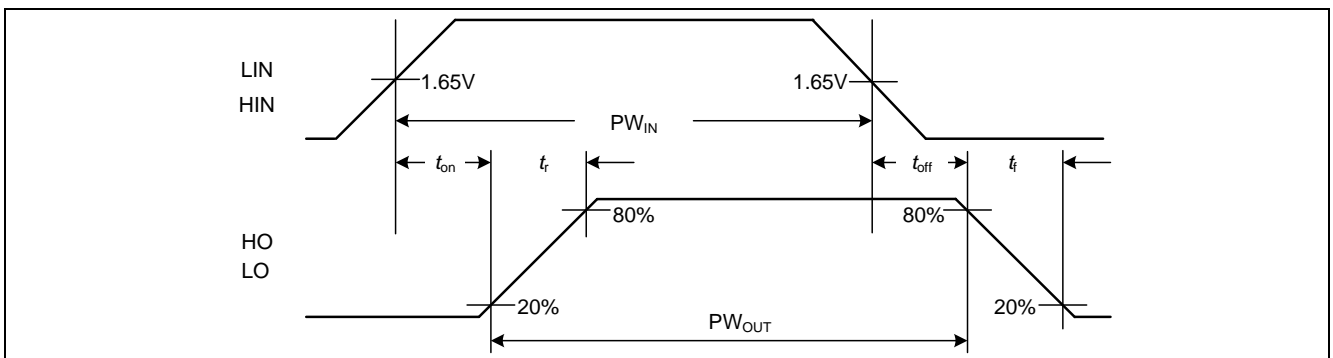


Figure 8 Input to output propagation delay times and switching times definition

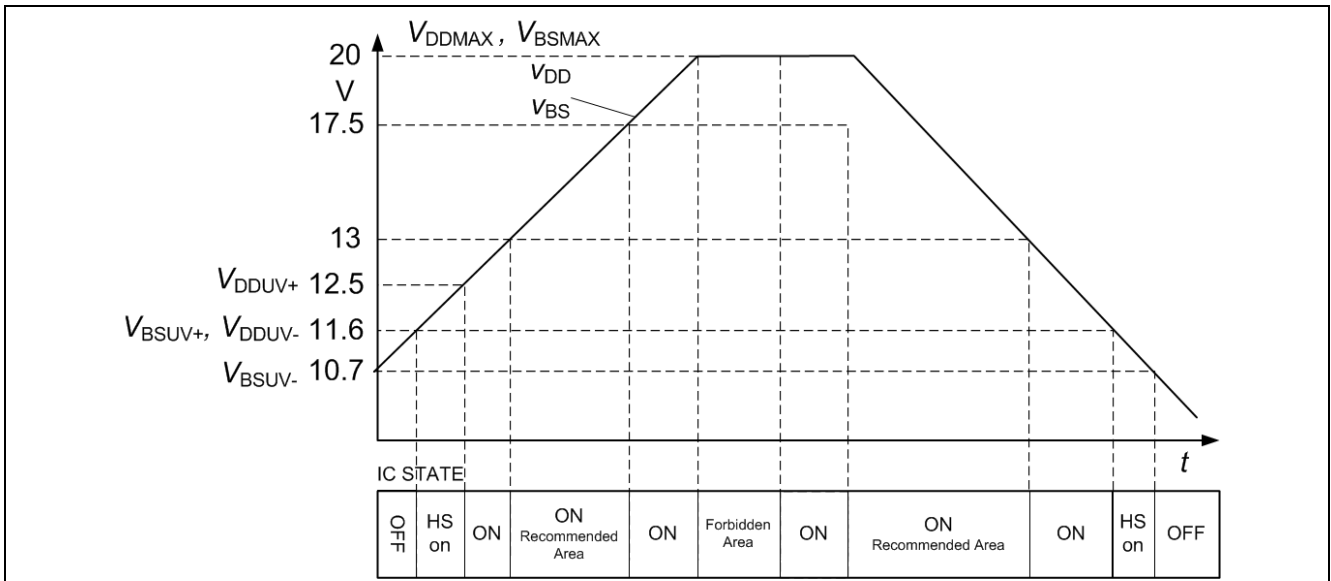


Figure 9 Operating areas (IGBT UVLO levels)

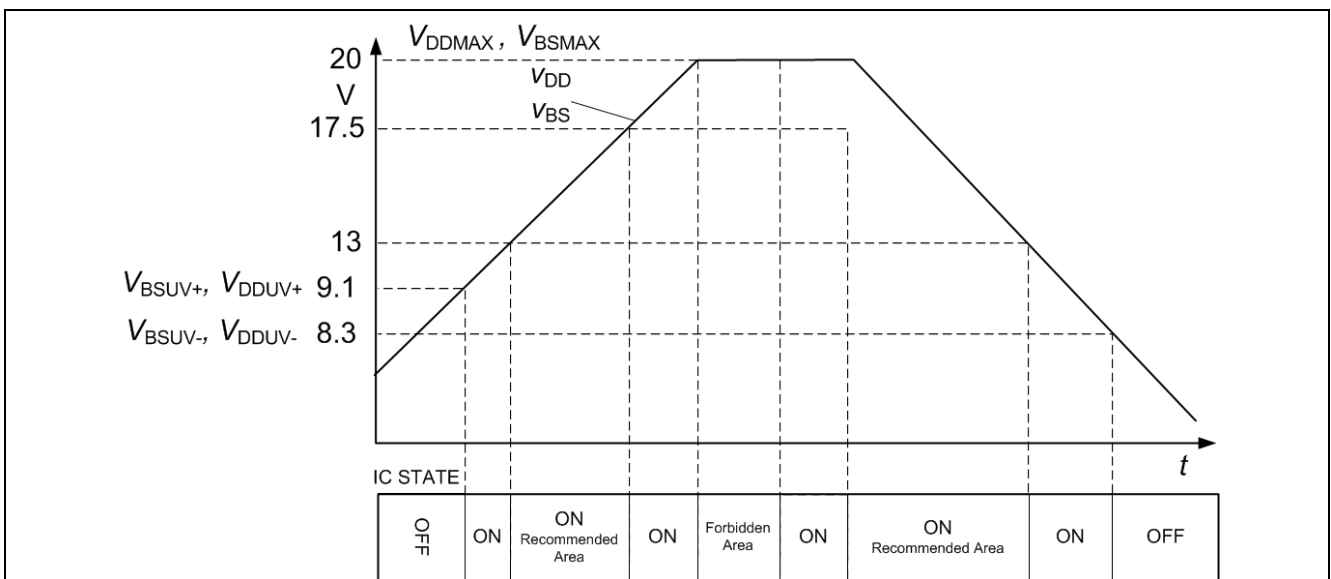


Figure 10 Operating areas (MOSFET UVLO levels)

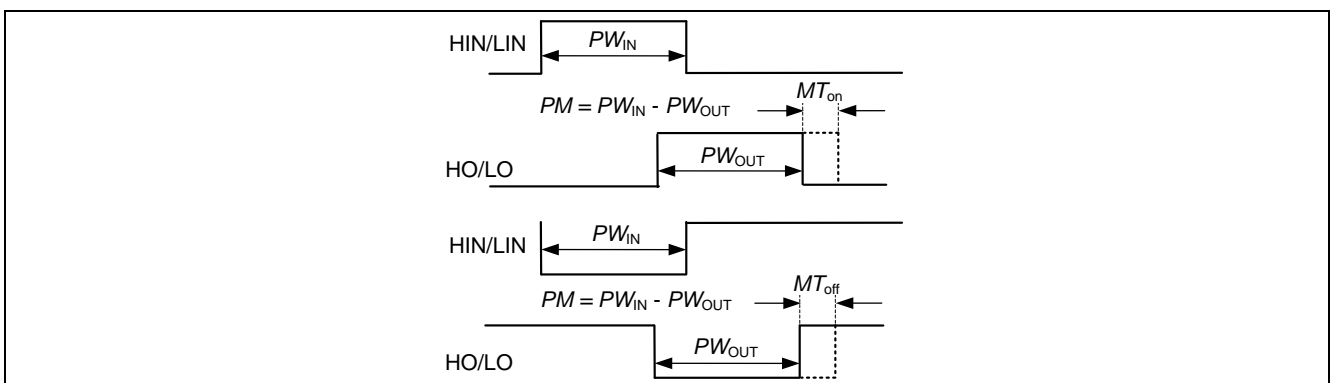


Figure 11 Output pulse width timing and matching delay timing diagram for positive logic

6 Package

6.1 PG-DSO-8

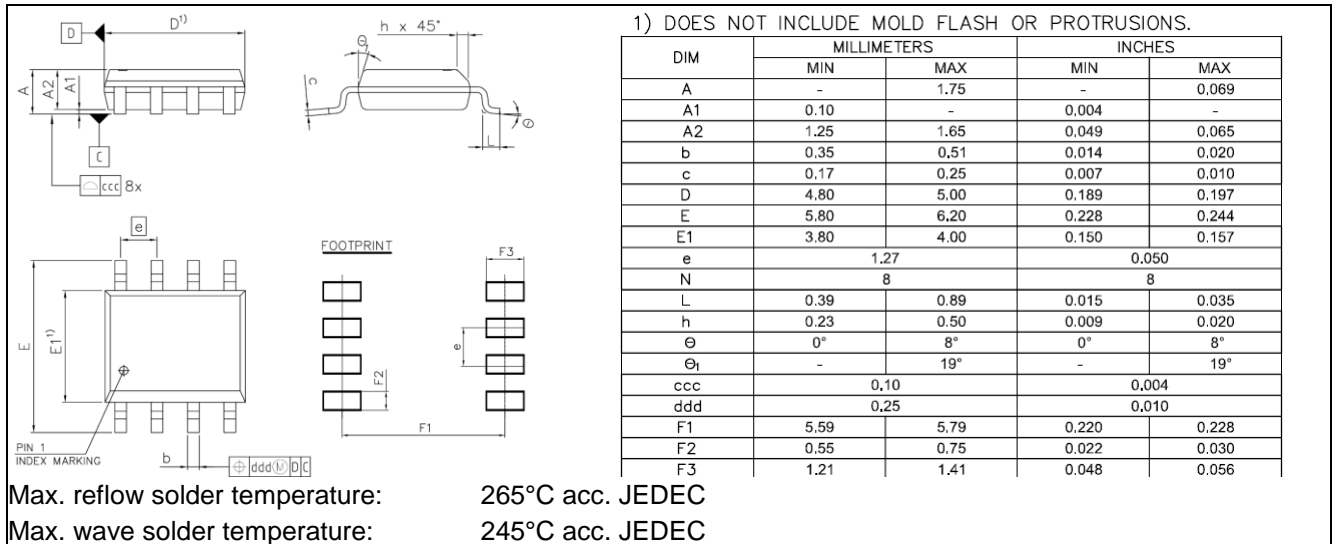


Figure 12 Package drawing

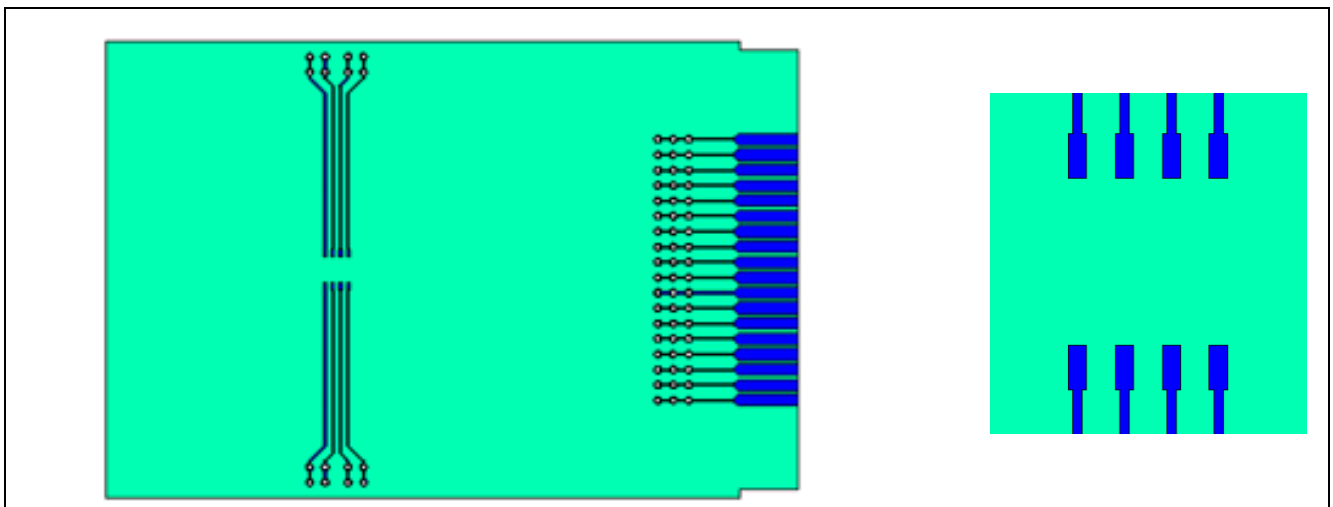


Figure 13 PCB reference layout
left: Reference layout
right: detail of footprint

The thermal coefficient is used to calculate the junction temperature, when the IC surface temperature is measured. The junction temperature is

$$T_j = \psi_{th(j-top)} \cdot P_d + T_{top}$$

Table 8 Data of reference layout

| Dimensions | Material | Metal (Copper) |
|------------------------------------|-------------------------------------|--------------------------------------|
| 76.2 × 114.3 × 1.5 mm ³ | FR4 ($\lambda_{therm} = 0.3$ W/mK) | 70µm ($\lambda_{therm} = 388$ W/mK) |

6.2 PG-DSO-14

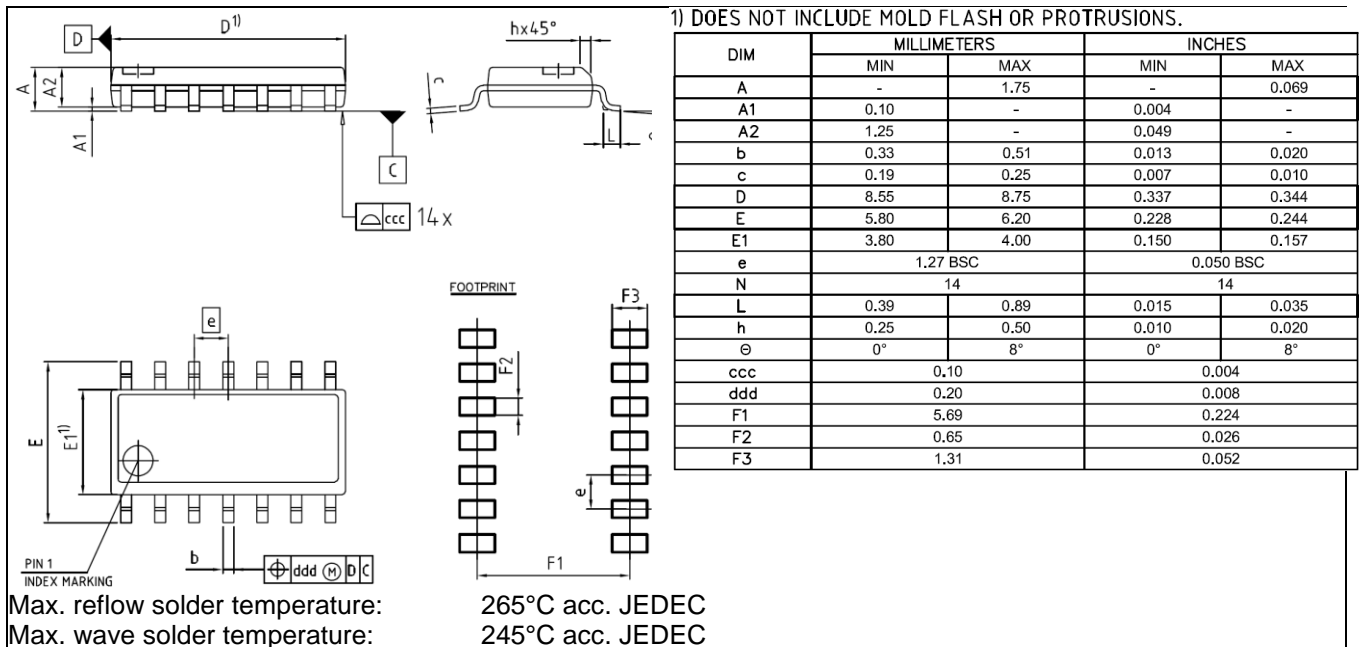


Figure 14 Package drawing

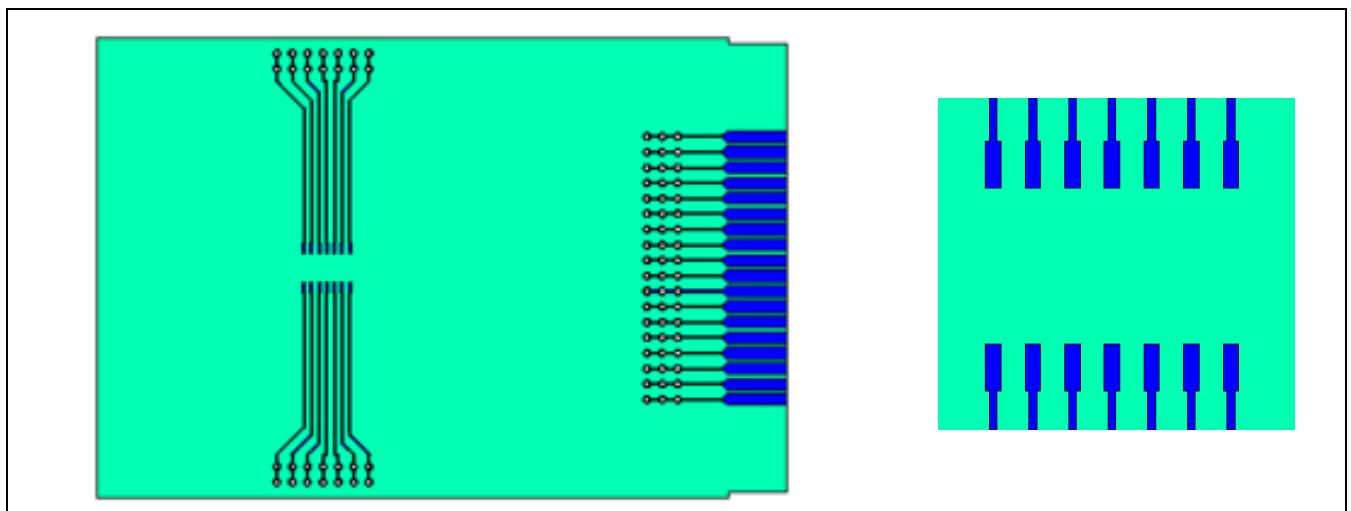


Figure 15 PCB reference layout (according to JEDEC 1s0P)
left: Reference layout
right: detail of footprint

The thermal coefficient is used to calculate the junction temperature, when the IC surface temperature is measured. The junction temperature is

$$T_j = \Psi_{th(j-top)} \cdot P_d + T_{top}$$

Table 9 Data of reference layout

| Dimensions | Material | Metal (Copper) |
|------------------------------------|-------------------------------------|--------------------------------------|
| 76.2 × 114.3 × 1.5 mm ³ | FR4 ($\lambda_{therm} = 0.3$ W/mK) | 70µm ($\lambda_{therm} = 388$ W/mK) |

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